Application/Control No. Applicant(s)/Patent Under Reexamination 10/031,913 DENIEGA ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 Mark K. Han 3767 **U.S. PATENT DOCUMENTS Document Number** Date Classification Name Country Code-Number-Kind Code MM-YYYY US-5,021,044 06-1991 Sharkawy, Ahmed 604/510 Α US-В US-С US-D US-Ε US-F US-G US-Н US-US-US-Κ US-US-M FOREIGN PATENT DOCUMENTS **Document Number** Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Ρ

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